

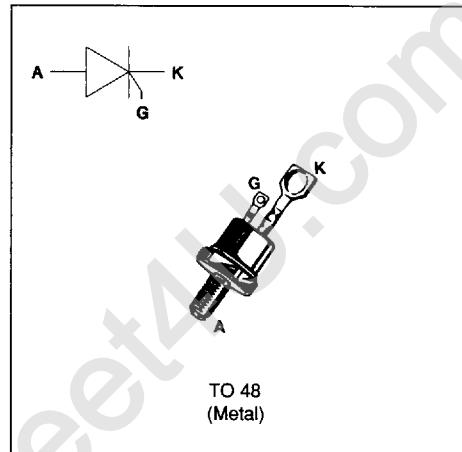
**FEATURES**

- HIGH SURGE CAPABILITY
- HIGH ON-STATE CURRENT
- HIGH STABILITY AND RELIABILITY

**DESCRIPTION**

The BTW 48 Family of Silicon Controlled Rectifiers uses a high performance glass passivated technology.

This general purpose Family of Silicon Controlled Rectifiers is designed for power supplies up to 400Hz on resistive or inductive load.

**ABSOLUTE RATINGS (limiting values)**

Symbol	Parameter	Value	Unit
I <sub>T</sub> (RMS)	RMS on-state current (180° conduction angle)	50	A
I <sub>T</sub> (AV)	Average on-state current (180° conduction angle, single phase circuit)	32	A
ITSM	Non repetitive surge peak on-state current ( T <sub>j</sub> initial = 25°C )	tp = 8.3 ms	520
		tp = 10 ms	500
I <sup>2</sup> t	I <sup>2</sup> t value	tp = 10 ms	A <sup>2</sup> s
dI/dt	Critical rate of rise of on-state current Gate supply : I <sub>G</sub> = 600 mA   dI <sub>G</sub> /dt = 1 A/μs	100	A/μs
T <sub>stg</sub> T <sub>j</sub>	Storage and operating junction temperature range	- 40 to + 150 - 40 to + 125	°C °C
T <sub>l</sub>	Maximum lead temperature for soldering during 10 s at 4.5 mm from case	230	°C

Symbol	Parameter	BTW 48-					Unit
		200	400	600	800	1200	
V <sub>D</sub> RM V <sub>RRM</sub>	Repetitive peak off-state voltage T <sub>j</sub> = 125 °C	200	400	600	800	1200	V

## THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
R <sub>th</sub> (c-h)	Contact (case to heatsink)	0.4	°C/W
R <sub>th</sub> (j-c) DC	Junction to case for DC	0.7	°C/W

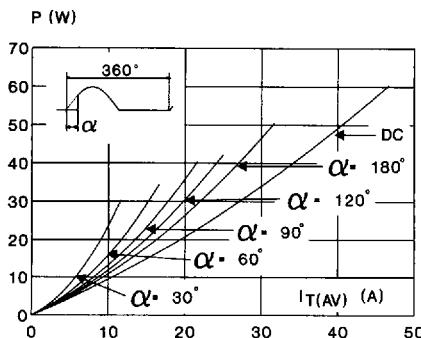
## GATE CHARACTERISTICS (maximum values)

P<sub>G</sub> (AV) = 1W P<sub>GM</sub> = 60W (tp = 20 μs) I<sub>FGM</sub> = 10A (tp = 20 μs) V<sub>FGM</sub> = 16V (tp = 20 μs) V<sub>RGM</sub> = 5 V.

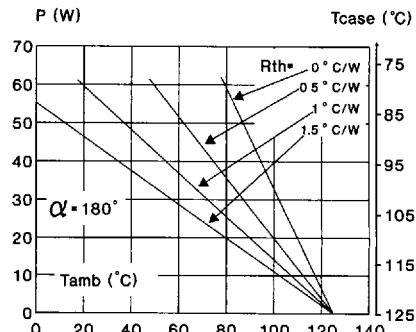
## ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions		Value	Unit
I <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =33Ω	T <sub>j</sub> =25°C	MAX	60
V <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =33Ω	T <sub>j</sub> =25°C	MAX	1.5
V <sub>GD</sub>	V <sub>D</sub> =V <sub>DRM</sub> R <sub>L</sub> =3.3kΩ	T <sub>j</sub> = 125°C	MIN	0.2
t <sub>gt</sub>	V <sub>D</sub> =V <sub>DRM</sub> I <sub>G</sub> = 200mA dI <sub>G</sub> /dt = 1.5A/μs	T <sub>j</sub> =25°C	TYP	2
I <sub>L</sub>	I <sub>G</sub> = 1.2 I <sub>GT</sub>	T <sub>j</sub> =25°C	TYP	60
I <sub>H</sub>	I <sub>T</sub> = 500mA gate open	T <sub>j</sub> =25°C	TYP	30
V <sub>TM</sub>	I <sub>TM</sub> = 100A tp= 380μs	T <sub>j</sub> =25°C	MAX	1.8
I <sub>DRM</sub> I <sub>RRM</sub>	V <sub>DRM</sub> Rated V <sub>RRM</sub> Rated	T <sub>j</sub> =25°C	MAX	0.02
		T <sub>j</sub> = 125°C		6
dV/dt	Linear slope up to V <sub>D</sub> =67%V <sub>DRM</sub> gate open	T <sub>j</sub> = 125°C	MIN	200
T <sub>q</sub>	V <sub>D</sub> =67%V <sub>DRM</sub> I <sub>TM</sub> = 100A V <sub>R</sub> = 50V dI <sub>TM</sub> /dt=30 A/μs dV <sub>D</sub> /dt= 20V/μs	T <sub>j</sub> = 125°C	TYP	100
				μs

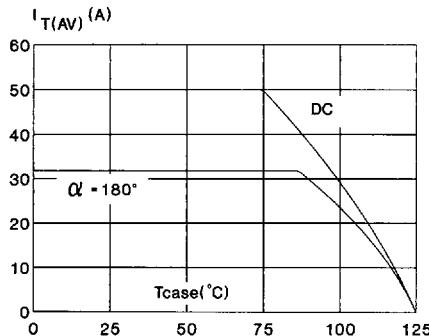
**Fig.1 :** Maximum average power dissipation versus average on-state current.



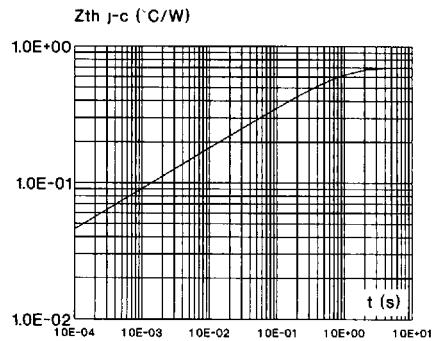
**Fig.2 :** Correlation between maximum average power dissipation and maximum allowable temperatures (T<sub>amb</sub> and T<sub>case</sub>) for different thermal resistances heatsink + contact.



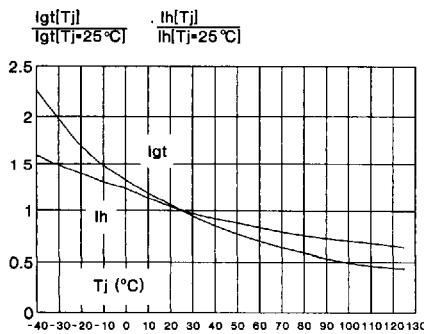
**Fig.3 :** Average on-state current versus case temperature.



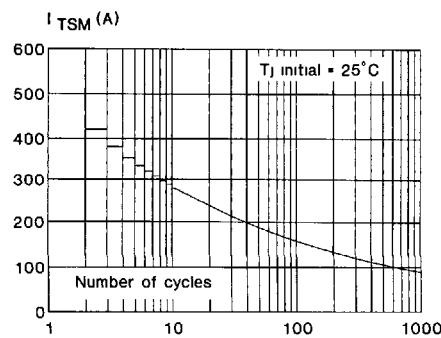
**Fig.4 :** Thermal transient impedance junction to ambient versus pulse duration.



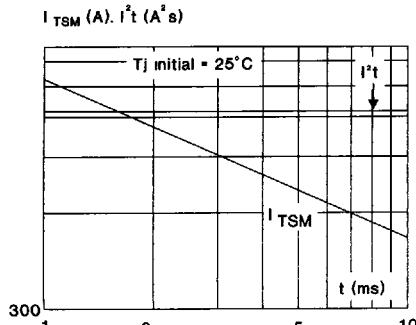
**Fig.5 :** Relative variation of gate trigger current versus junction temperature.



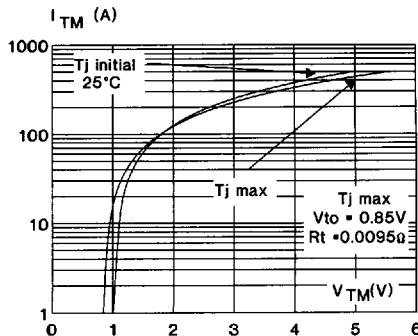
**Fig.6 :** Non repetitive surge peak on-state current versus number of cycles.



**Fig.7 : Non repetitive surge peak on-state current for a sinusoidal pulse with width :  $t \leq 10$  ms, and corresponding value of  $I^2t$ .**

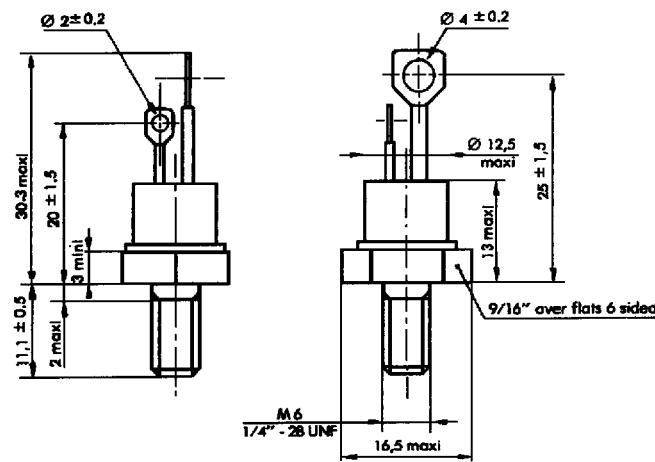


**Fig.8 : On-state characteristics (maximum values).**



#### PACKAGE MECHANICAL DATA (in millimeters)

TO 48 Metal



Cooling method : A

Marking : type number

Weight : 13.5 g

Polarity : Anode (or A2) to case

Stud torque : 3.5 mAN min / 3.8 mAN max